

# 4 Bit 100 Mbps Configurable Level Translator

#### **General Description**

The ET5014AM is a 4-bit bidirectional level translator in which the input and output ports are switched automatically without direction control. The data path of each channel can be either from I/O\_V\_n to I/O\_V\_cn or from I/O\_V\_cn to I/O\_V\_n. All of the I/O ports are designed to track two different power supply rails,  $V_{CC}$  and  $V_L$  respectively. Both of the supply voltage are configurable from 1.1V to 5.0V. The  $V_{CC}$  and  $V_L$  supplies are independent which allows a logic signal on the  $V_L$  side to be translated to either a higher or a lower logic signal voltage on the  $V_{CC}$  side, and vice-versa.

The ET5014AM has high output current capability, which allows the translator to drive high capacitive loads such as most high frequency EMI filters. The enable pin(EN) is used to reduce the power consumption. The EN pin can be used to disable both I/O ports by putting them in 3-state which significantly reduces the supply current from both  $V_{CC}$  and  $V_L$ . The EN signal is referenced to the  $V_L$  supply.

ET5014AM operates over an ambient temperature range of -40°C to +105°C.

#### **Features**

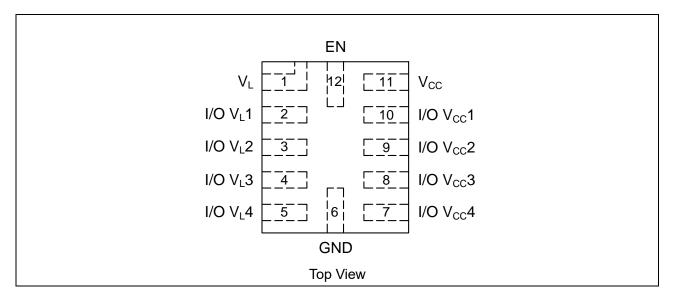
- Wide V<sub>CC</sub>, V<sub>L</sub> Operating Range: 1.1V to 5.0V
- V<sub>L</sub> and V<sub>CC</sub> are Independent
- V<sub>L</sub> may be Greater than, Equal to, or Less than V<sub>CC</sub>
- High 100 pF Capacitive Drive Capability
- High-Speed with 100 Mbps Guaranteed Date Rate for V<sub>CC</sub>, V<sub>L</sub> > 1.8V
- Low Bit-to-Bit Skew
- Over-voltage Tolerant Enable and I/O Pins
- Non-preferential Power Up Sequencing
- Power-Off Protection
- Automotive AEC-Q100 Grade 2 Qualified
- Packaging Information

Part No. Package		MSL
ET5014AM	QFN12 (1.7 mm x 2.0 mm)	Level 1

#### **Application**

- Automotive Infotainment and Cluster
- Automotive Other Devices

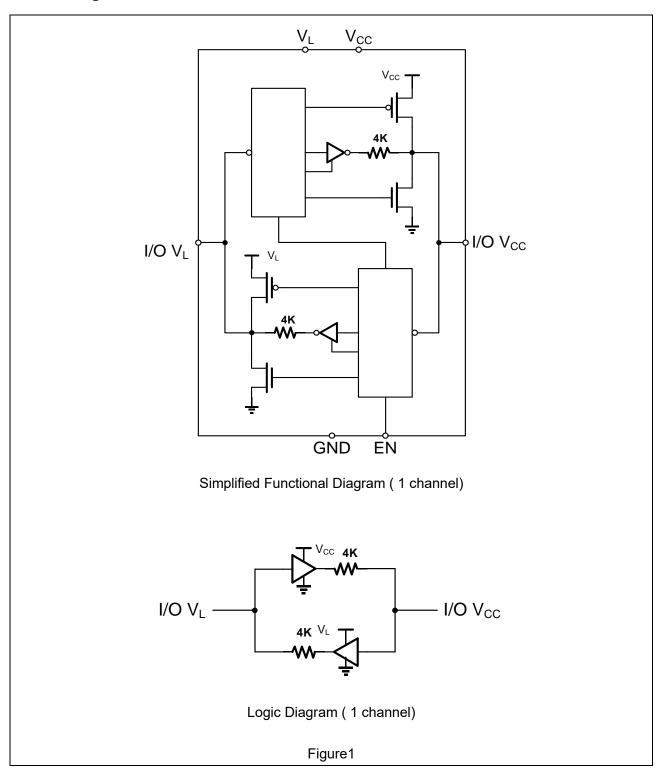
# **Pin Configuration**



### **Pin Function**

Pin Number	Pin Name	Description
11	Vcc	V <sub>CC</sub> Input Voltage
1	V <sub>L</sub>	V <sub>∟</sub> Input Voltage
6	GND	Ground
12	EN	Output Enable
7~10	I/O Vccn	I/O Port, Referenced to V <sub>CC</sub>
2~5	I/O V <sub>L</sub> n	I/O Port, Referenced to V <sub>L</sub>

# **Block Diagram**



#### **Function Description**

The ET5014AM auto-sense translator provides bi-directional logic voltage level shifting to transfer data in multiple supply voltage systems. These level translators have two supply voltages,  $V_L$  and  $V_{CC}$ , which set the logic levels on the input and output sides of the translator. When used to transfer data from the I/O  $V_L$  to the I/O  $V_{CC}$  ports, input signals referenced to the  $V_L$  supply are translated to output signals with a logic level matched to  $V_{CC}$ . In a similar manner, the I/O  $V_{CC}$  to I/O  $V_L$  translation shifts input signals with a logic level compatible to  $V_{CC}$  to an output signal matched to  $V_L$ .

The ET5014AM translator consists of bi-directional channels that independently determine the direction of the data flow without requiring a directional pin. One-shot circuits are used to detect the rising or falling input signals. In addition, the one-shots decrease the rise and fall times of the output signal for high-to-low and low-to-high transitions.

Auto-sense translators such as the ET5014AM have a wide bandwidth, but a relatively small DC output current rating. The high bandwidth of the bi-directional I/O circuit is used to quickly transform from an input to an output driver and vice versa. The I/O ports have a modest DC current output specification so that the output driver can be over driven when data is sent in the opposite direction. For proper operation, the input driver to the auto-sense translator should be capable of driving 2 mA of peak output current. The bi-directional configuration of the translator results in both input stages being active for a very short time period. Although the peak current from the input signal circuit is relatively large, the average current is small and consistent with a standard CMOS input stage.

The ET5014AM translator has an Enable pin (EN) that provides tri-state operation at the I/O pins. Driving the Enable pin to a low logic level minimizes the power consumption of the device and drives the I/O  $V_{CC}$  and I/O  $V_{L}$  pins to a high impedance state. Normal translation operation occurs when the EN pin is equal to a logic high signal. The EN pin is referenced to the  $V_{L}$  supply and has Over-Voltage Tolerant (OVT) protection.

The ET5014AM translator can function as a non-inverting uni-directional translator. One advantage of using the translator as a uni-directional device is that each I/O pin can be configured as either an input or output. The configurable input or output feature is especially useful in applications such as SPI that use multiple uni-directional I/O lines to send data to and from a device. The flexible I/O port of the auto sense translator simplifies the trace connections on the PCB.

The values of the  $V_L$  and  $V_{CC}$  supplies can be set to anywhere between 1.1V and 5.0V. Design flexibility is maximized because  $V_L$  may be either greater than or less than the  $V_{CC}$  supply. In contrast, the majority of the competitive auto sense translators has a restriction that the value of the  $V_L$  supply must be equal to less than  $(V_{CC} - 0.4) V$ .

The sequencing of the power supplies will not damage the device during power-up operation. In addition, the I/O  $V_{CC}$  and I/O  $V_{L}$  pins are in the high impedance state if either supply voltage is equal to 0V. For optimal performance, 0.01uF to 0.1uF decoupling capacitors should be used on the  $V_{L}$  and  $V_{CC}$  power supply pins. Ceramic capacitors are a good design choice to filter and bypass any noise signals on the voltage lines to the ground plane of the PCB. The noise immunity will be maximized by placing the capacitors as close as possible to the supply and ground pins, along with minimizing the PCB connection traces.

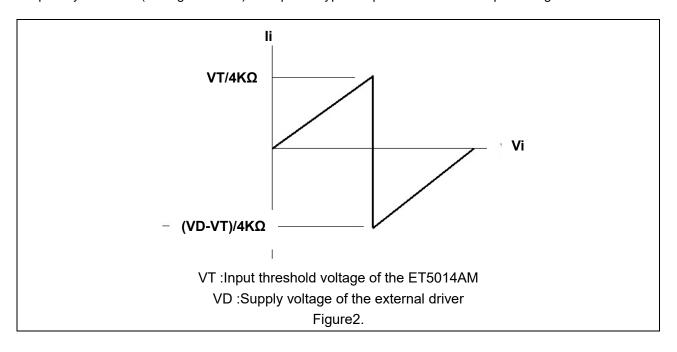
The ET5014AM translators have a power down feature that provides design flexibility. The output ports are disabled when either power supply is off ( $V_L$  or  $V_{CC} = 0V$ ). This feature causes all of the I/O pins to be in the power saving high impedance state.

#### **About Pull-Up/Pull-Down Resistors**

Do not use any pull-up or pull-down resistors. This device has bus-hold circuits: pull-up or pull-down resistors are not recommended because they interfere with the output state. The current through these resistors may exceed the hold drive's bus-hold current (see figure below), resulting in data transition and/or auto-direction sensing failures. The bus-hold feature eliminates the need for extra resistors.

#### **Input Driver Requirements**

For correct operation, the device driving the data I/Os of the ET5014AM must have a minimum drive capability of ±2 mA (see figure below) for a plot of typical input current versus input voltage.



#### **Absolute Maximum Ratings**

Symbol	Parameter	Condition	Value	Unit
Vcc	High-side DC Supply Voltage		−0.5 to +5.5	V
VL	Low-side DC Supply Voltage		−0.5 to +5.5	٧
I/O Vcc	V <sub>CC</sub> -Referenced DC Input/Output Voltage		−0.5 to +5.5	V
I/O VL	V <sub>L</sub> −Referenced DC Input/Output Voltage		−0.5 to +5.5	V
Vı	Enable Control Pin DC Input Voltage		−0.5 to +5.5	V
lıĸ	DC Input Diode Current	Vı < GND	-50	mA
Іок	DC Output Diode Current	Vo < GND	-50	mA
Icc	DC Supply Current Through V <sub>CC</sub>		±100	mA
IL	DC Supply Current Through V <sub>L</sub>		±100	mA
I <sub>GND</sub>	DC Ground Current Through Ground Pin		±100	mA
TJ	Max Junction Temperature		+150	°C
T <sub>STG</sub>	Storage Temperature		−65 to +150	°C
ESD <sup>(*)</sup>	Human Body Model		±4000	
E9D,	Charged Device Model		±2000	V
LU(*)	Latch up Current Maximum Rating		±300	mA

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

*Note\**. This device series incorporates ESD protection and is tested by the following methods:

HBM tested per AEC-Q100-002(EIA/JESD22-A114);

CDM tested per AEC-Q100-011(EIA/JESD22-C101);

Latch up Current Maximum Rating tested per AEC-Q100-004(EIA/JESD78E).

#### **Recommended Operating Conditions**

Symbol	Parai	Min	Max	Unit	
Vcc	High-side Positive	DC Supply Voltage	1.1	5.0	V
VL	Low-side Positive	DC Supply Voltage	1.1	5.0	V
Vı	Enable Contro	GND	5.0	V	
V	Due les ut/Outeut Veltere	I/O Vcc	GND	5.0	V
V <sub>IO</sub>	Bus Input/Output Voltage	I/O VL	GND	5.0	V
TA	Operating Temp	-40	+105	°C	
\( \dagger \dagger \land \land \dagger \land \dagger \	Input Transition Rise or Rate $V_{I}$ , $V_{IO}$ from 30% to 70% of $V_{CC}$ ; $V_{CC}$ = 3.3 V $\pm$ 0.3 V		0	10	20
△t/△V			0	10	ns

#### **DC Electrical Characteristics**

( *Note*: VS is the corresponding supply for IO, i.e.  $V_{CC}$  for IO\_ $V_{CC}$  and  $V_L$  for IO\_ $V_L$ )

Ou made al	Downwood	To at O and iti and (1)	V/ (2)	V (2)	-40	-40°C to +10		11
Symbol	Parameter	Test Conditions <sup>(1)</sup>	V <sub>CC</sub> (2)	<b>V</b> <sub>L</sub> <sup>(3)</sup>	Min	Typ (4)	Max	Unit
VIH	I/O Input HIGH Voltage		1.1-5.0	1.1-5.0	0.65* Vs	-	-	V
VIL	I/O Input LOW Voltage		1.1-5.0	1.1-5.0	-	-	0.35* Vs	V
V <sub>IH-EN</sub>	Control Pin Input HIGH Voltage	T <sub>A</sub> =+25°C	1.1-5.0	1.1-5.0	0.65* Vs	-	-	V
VIL-EN	Control Pin Input LOW Voltage	T <sub>A</sub> =+25°C	1.1-5.0	1.1-5.0	-	-	0.35* Vs	V
V <sub>OH</sub>	I/O Output HIGH Voltage	I/O source current = 20uA	1.1-5.0	1.1-5.0	Vs-0.2	-	-	>
Vol	I/O Output LOW Voltage	I/O source current = 20uA	1.1-5.0	1.1-5.0	-	-	0.2	٧
lα	Static Supply Current	EN = $V_L$ , $I_O = 0$ A, (I/O-in = 0 V or $V_S$ , I/O-out = float)	1.1-5.0	1.1-5.0	-	-	1	uA
ITS	Tristate Output  Mode Supply  Current	EN = 0 V, (I/O-in = 0 V or Vs, I/O-out = float)	1.1-5.0	1.1-5.0	-	-	1	uA
l <sub>OZ</sub>	Tristate Output  Mode I/O  Leakage Current	EN = 0 V	1.1-5.0	1.1-5.0	-	-	±1	uA
Iı	Control Pin Input Current	T <sub>A</sub> = +25°C	1.1-5.0	1.1-5.0	-	-	±1	uA
	Power off	I/O Vcc = 0 to Vcc,	0	0	-	-	1	
I <sub>OFF</sub>	Leakage Current	$I/O V_c = 0 \text{ to } V_c$	1.1-5.0	0	-	-	1	uA
	Leakage Current	1/O VL - U 10 VL	0	1.1-5.0	-	-	1	

#### Notes:

- 1. Normal test conditions are  $V_I = 0$  V,  $C_{IOVCC} \le 15$  pF and  $C_{IOVL} \le 15$  pF, unless otherwise specified.
- 2.  $V_{CC}$  is the supply voltage associated with the I/O  $V_{CC}$  port, and  $V_{CC}$  ranges from +1.1V to 5.0V under normal operating conditions.
- 3.  $V_L$  is the supply voltage associated with the I/O  $V_L$  port, and  $V_L$  ranges from +1.1V to 5.0V under normal operating conditions.
- **4**. Typical values are for  $V_{CC}$  = +2.8V,  $V_L$  = +1.8V and  $T_A$  = +25°C. All units are production tested at  $T_A$  = +25°C. Limits over the operating temperature range are guaranteed by design.

# **Timing Characteristics**

Symbol	Doromo	tor	Test Conditions <sup>(5)</sup>	V <sub>CC</sub> (6)	V <sub>L</sub> (7)	-40	°C to +10	5°C	Unit
Symbol	Paramet	ter	rest Conditions(9)	V <sub>CC</sub> (o)	V <sub>L</sub> ('')	Min	Typ <sup>(8)</sup>	Max	Unit
т	I/O Dies T	ima	C =15pF	1.1-5.0	1.1-5.0			9.5	no
$T_R$	I/O Rise Time		C <sub>IO</sub> =15pF	1.8-5.0	1.8-5.0			7.5	ns
_	1/O F-11 T		0 -45-5	1.1-5.0	1.1-5.0			9.5	
$T_F$	I/O Fall T	ime	C <sub>IO</sub> =15pF	1.8-5.0	1.8-5.0			7.5	ns
-	I/O V <sub>CC</sub> One	-Shot	(9)	1.8	4.4.5.0		20		
Zovcc	Output Impe	dance	(3)	5.0	1.1-5.0		6.0		Ω
-	I/O V <sub>L</sub> One-	-Shot	(0)	4.4.5.0	1.8		20		
$Z_{\text{OVL}}$	Output Impe	dance	(9)	1.1-5.0	5.0		6.0		Ω
				1.1-5.0	1.1-5.0			35	
			Ciovec=15pF	1.8-5.0	1.8-5.0			13	
				1.1-5.0	1.1-5.0			35	
	Propagation	-	Ciovec=30pF	1.8-5.0	1.8-5.0			15	
t <sub>PD</sub>	(Driving I/C			1.1-5.0	1.1-5.0			37	ns
	or I/O V <sub>L</sub> )		C <sub>IOVCC</sub> =50pF	1.8-5.0	1.8-5.0			15	-
				1.1-5.0	1.1-5.0			53	
			C <sub>IOVCC</sub> =100pF	1.8-5.0	1.8-5.0			24	
tsĸ	Channel		Ciovcc =CiovL = 5pF	1.1-5.0	1.1-5.0			0.15	ns
lin_peak	Input Dri Maximu Peak Cur	m	$I/O_{L}V_{CC} = 1MHz$ Square Wave, Amplitude =V <sub>CC</sub> , or $I/O_{L}V_{L} = 1$ MHz Square Wave, Amplitude = V <sub>L</sub> EN = V <sub>L</sub> ; <sup>(9)</sup>	1.1-5.0	1.1-5.0			2	mA
t	I/O Output Enable	t <sub>PZH</sub>	C <sub>IO</sub> = 15 pF, I/O_V <sub>L</sub> = V <sub>L</sub>	1.1-5.0	1.1-5.0			170	ne
ten	Time	tpzl	C <sub>IO</sub> = 15pF, I/O_V <sub>L</sub> = 0V	1.1-5.0	1.1-5.0			170	ns
toic	I/O Output	t <sub>PHZ</sub>	C <sub>IO</sub> = 15 pF, I/O_V <sub>L</sub> = V <sub>L</sub>	1.1-5.0	1.1-5.0			180	ne
t <sub>DIS</sub> Disable Time		<b>t</b> PLZ	C <sub>IO</sub> = 15pF, I/O_V <sub>L</sub> = 0V	1.1-5.0	1.1-5.0			175	ns

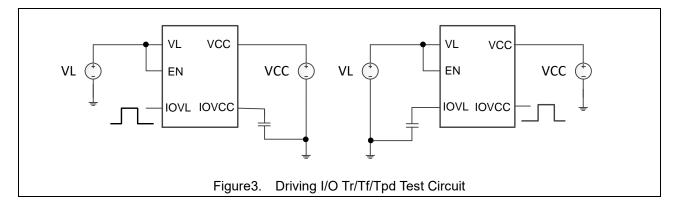
### **Timing Characteristics (Continued)**

Cumbal	Doromotor	Test Conditions <sup>(5)</sup>	V (6)	V (7)	-40	°C to +10	5°C	l lmi4
Symbol	Parameter	rest Conditions(9)	V <sub>CC</sub> (6)	<b>V</b> <sub>L</sub> <sup>(7)</sup>	Min	Typ <sup>(8)</sup>	Max	Unit
			1.1-5.0	1.1-5.0	40			
		C <sub>IO</sub> =15pF	1.5-5.0	1.5-5.0	80			
		C <sub>10</sub> =15pr	1.8-5.0	1.8-5.0	100			
			2.3-5.0	2.3-5.0	160			
			1.1-5.0	1.1-5.0	40			
		C <sub>IO</sub> =30pF  Maximum  Data Rate  C <sub>IO</sub> =50pF	1.5-5.0	1.5-5.0	72			
			1.8-5.0	1.8-5.0	94			]
	Maximum		2.3-5.0	2.3-5.0	140			
MDR			1.1-5.0	1.1-5.0	35			Mbps
	Dala Nale		1.5-5.0	1.5-5.0	63			
			1.8-5.0	1.8-5.0	87			
			2.3-5.0	2.3-5.0	120			
			1.1-5.0	1.1-5.0	30			
		C=100pF	1.5-5.0	1.5-5.0	55			
		C <sub>IO</sub> =100pF	1.8-5.0	1.8-5.0	80			
			2.3-5.0	2.3-5.0	100			

#### Notes:

- **5**. Normal test conditions are  $V_1 = 0V$ ,  $C_{1OVCC} \le 15pF$  and  $C_{1OVL} \le 15pF$ , unless otherwise specified.
- **6**.  $V_{CC}$  is the supply voltage associated with the I/O  $V_{CC}$  port, and  $V_{CC}$  ranges from +1.1V to 5.0V under normal operating conditions.
- **7**.  $V_L$  is the supply voltage associated with the I/O  $V_L$  port, and  $V_L$  ranges from +1.1V to 5.0V under normal operating conditions.
- **8**. Typical values are for  $V_{CC} = 2.8V$ ,  $V_L = 1.8V$  and  $T_A = 25$ °C. All units are production tested at  $T_A = 25$ °C. Limits over the operating temperature range are guaranteed by design.
- 9. Guaranteed by design.

#### **Test Circuit and Timing**



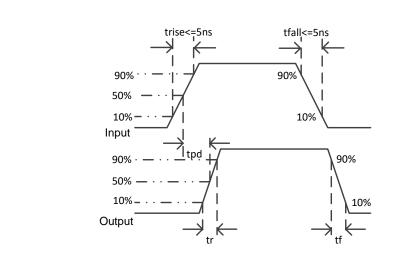
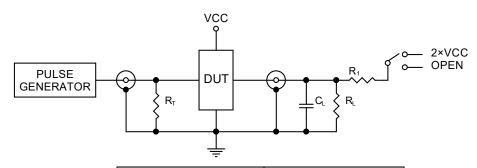


Figure 4. Driving I/O Tr/Tf/Tpd Test Timing



Test	Switch
tpzн, tpнz	open
tpzl, tplz	2 × Vcc

 $C_L$  = 15pF or equivalent (Includes jig and probe capacitance)

 $R_L = R_1 = 50k\Omega$  or equivalent

 $R_T = Z_{OUT}$  of pulse generator (typically 50 $\Omega$ )

Figure5. Enable/Disable Test Circuit

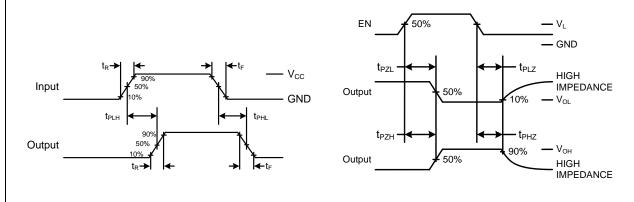
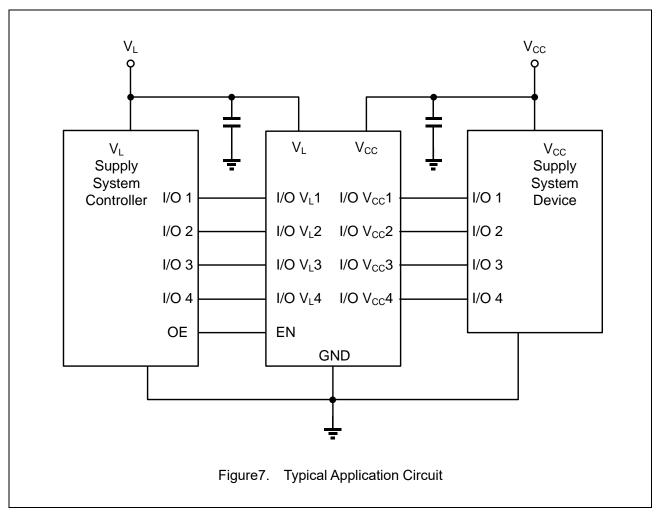


Figure6. Enable/Disable Test Timeing

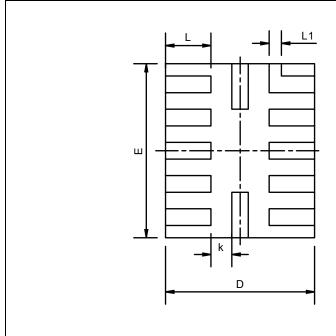
### **Typical Application Circuits**

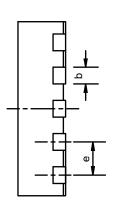


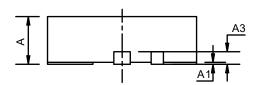
<sup>\*:</sup> This electric circuit only supplies for reference.

# **Package Dimension**

### QFN12



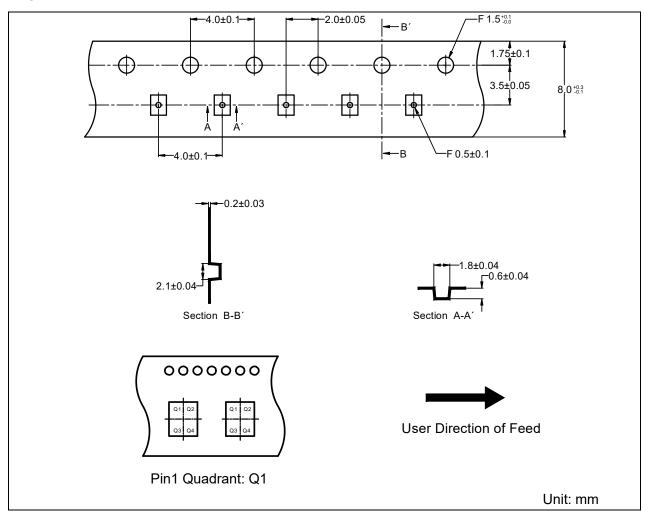




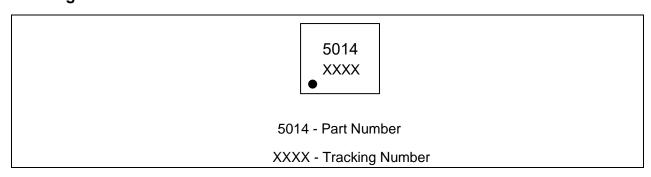
# COMMON DIMENSIONS (UNITS OF MEASURE=MILLIMETER)

SYMBOL	MIN	MAX	
Α	0.450	0.550	
A1	0.000	0.050	
A3	0.152	2REF.	
b	0.150	0.250	
D	1.600	1.800	
Е	1.900	2.100	
е	0.400	) TYP.	
L	0.450	0.550	
L1	0.150 REF.		
k	0.200	MIN.	

### **Tape Information**



### Marking



### **Revision History and Checking Table**

Version	Date	Revision Item	Modifier	Function & Spec	Package & Tape
VCISIOII	Date	Revision item	Woulder	Checking	Checking
1.0	2022-1-14	Initial Version	Ma Yong Jian	Ma Yong Jian	Zhujl
1.1	2022-6-18	Updated form	Shi bo	Shi Liang Jun	Zhu Jun Li